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Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	625
Number of Logic Elements/Cells	5000
Total RAM Bits	169984
Number of I/O	100
Number of Gates	-
Voltage - Supply	1.14V ~ 1.26V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	144-LQFP
Supplier Device Package	144-TQFP (20x20)
Purchase URL	https://www.e-xfl.com/product-detail/lattice-semiconductor/lfxp2-5e-6tn144c

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Introduction

LatticeXP2 devices combine a Look-up Table (LUT) based FPGA fabric with non-volatile Flash cells in an architecture referred to as flexiFLASH.

The flexiFLASH approach provides benefits including instant-on, infinite reconfigurability, on chip storage with FlashBAK embedded block memory and Serial TAG memory and design security. The parts also support Live Update technology with TransFR, 128-bit AES Encryption and Dual-boot technologies.

The LatticeXP2 FPGA fabric was optimized for the new technology from the outset with high performance and low cost in mind. LatticeXP2 devices include LUT-based logic, distributed and embedded memory, Phase Locked Loops (PLLs), pre-engineered source synchronous I/O support and enhanced sysDSP blocks.

Lattice Diamond[®] design software allows large and complex designs to be efficiently implemented using the LatticeXP2 family of FPGA devices. Synthesis library support for LatticeXP2 is available for popular logic synthesis tools. The Diamond software uses the synthesis tool output along with the constraints from its floor planning tools to place and route the design in the LatticeXP2 device. The Diamond tool extracts the timing from the routing and back-annotates it into the design for timing verification.

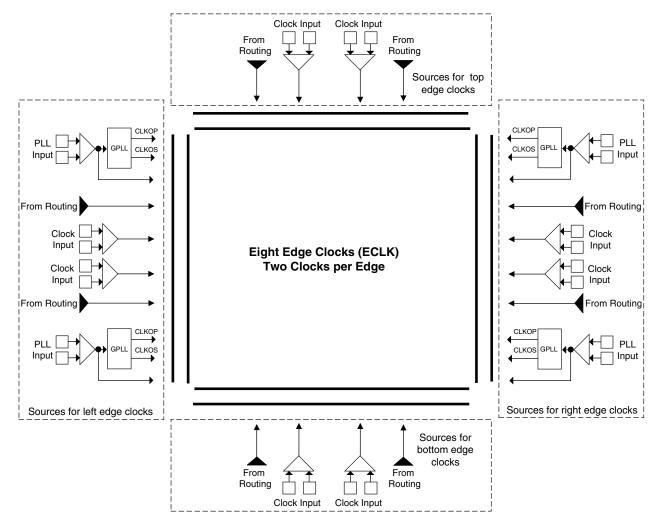
Lattice provides many pre-designed Intellectual Property (IP) LatticeCORE[™] modules for the LatticeXP2 family. By using these IPs as standardized blocks, designers are free to concentrate on the unique aspects of their design, increasing their productivity.



Edge Clock Sources

Edge clock resources can be driven from a variety of sources at the same edge. Edge clock resources can be driven from adjacent edge clock PIOs, primary clock PIOs, PLLs and clock dividers as shown in Figure 2-8.

Figure 2-8. Edge Clock Sources



Note: This diagram shows sources for the XP2-17 device. Smaller LatticeXP2 devices have two GPLLs.



LatticeXP2-30 and smaller devices have six secondary clock regions. All devices in the LatticeXP2 family have four secondary clocks (SC0 to SC3) which are distributed to every region.

The secondary clock muxes are located in the center of the device. Figure 2-12 shows the mux structure of the secondary clock routing. Secondary clocks SC0 to SC3 are used for clock and control and SC4 to SC7 are used for high fan-out signals.



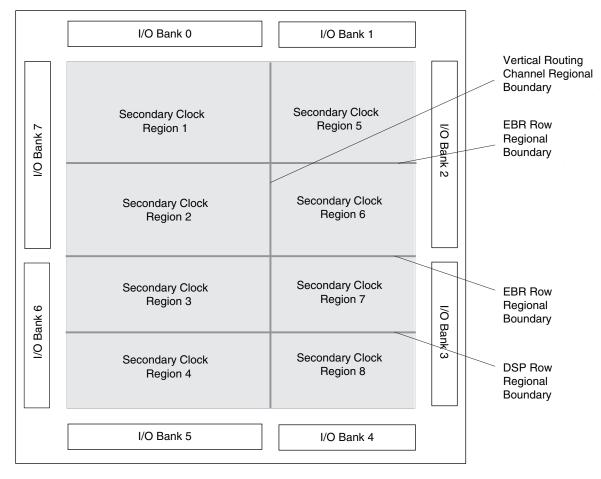
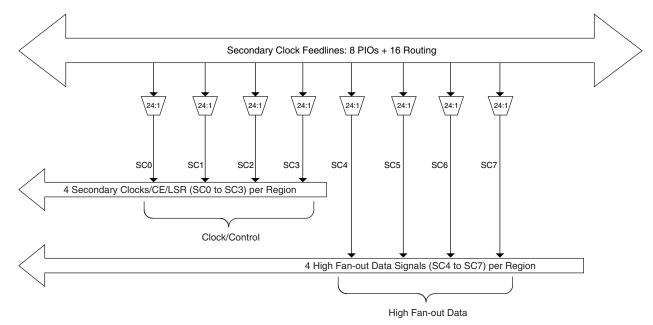




Figure 2-12. Secondary Clock Selection

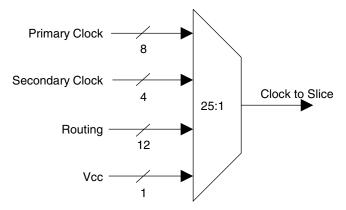


Slice Clock Selection

Figure 2-13 shows the clock selections and Figure 2-14 shows the control selections for Slice0 through Slice2. All the primary clocks and the four secondary clocks are routed to this clock selection mux. Other signals, via routing, can be used as clock inputs to the slices. Slice controls are generated from the secondary clocks or other signals connected via routing.

If none of the signals are selected for both clock and control, then the default value of the mux output is 1. Slice 3 does not have any registers; therefore it does not have the clock or control muxes.

Figure 2-13. Slice0 through Slice2 Clock Selection

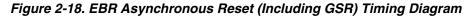




For further information on the sysMEM EBR block, please see TN1137, LatticeXP2 Memory Usage Guide.

EBR Asynchronous Reset

EBR asynchronous reset or GSR (if used) can only be applied if all clock enables are low for a clock cycle before the reset is applied and released a clock cycle after the low-to-high transition of the reset signal, as shown in Figure 2-18. The GSR input to the EBR is always asynchronous.



Reset	
Clock	
Clock —————— Enable	

If all clock enables remain enabled, the EBR asynchronous reset or GSR may only be applied and released after the EBR read and write clock inputs are in a steady state condition for a minimum of 1/f_{MAX} (EBR clock). The reset release must adhere to the EBR synchronous reset setup time before the next active read or write clock edge.

If an EBR is pre-loaded during configuration, the GSR input must be disabled or the release of the GSR during device Wake Up must occur before the release of the device I/Os becoming active.

These instructions apply to all EBR RAM and ROM implementations.

Note that there are no reset restrictions if the EBR synchronous reset is used and the EBR GSR input is disabled.

sysDSP™ Block

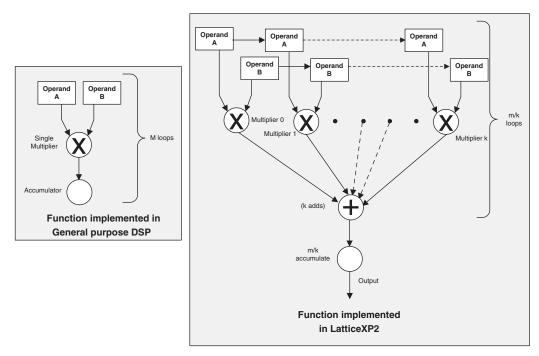
The LatticeXP2 family provides a sysDSP block making it ideally suited for low cost, high performance Digital Signal Processing (DSP) applications. Typical functions used in these applications include Bit Correlators, Fast Fourier Transform (FFT) functions, Finite Impulse Response (FIR) Filter, Reed-Solomon Encoder/Decoder, Turbo Encoder/ Decoder and Convolutional Encoder/Decoder. These complex signal processing functions use similar building blocks such as multiply-adders and multiply-accumulators.

sysDSP Block Approach Compare to General DSP

Conventional general-purpose DSP chips typically contain one to four (Multiply and Accumulate) MAC units with fixed data-width multipliers; this leads to limited parallelism and limited throughput. Their throughput is increased by higher clock speeds. The LatticeXP2 family, on the other hand, has many DSP blocks that support different data-widths. This allows the designer to use highly parallel implementations of DSP functions. The designer can optimize the DSP performance vs. area by choosing appropriate levels of parallelism. Figure 2-19 compares the fully serial and the mixed parallel and serial implementations.







sysDSP Block Capabilities

The sysDSP block in the LatticeXP2 family supports four functional elements in three 9, 18 and 36 data path widths. The user selects a function element for a DSP block and then selects the width and type (signed/unsigned) of its operands. The operands in the LatticeXP2 family sysDSP Blocks can be either signed or unsigned but not mixed within a function element. Similarly, the operand widths cannot be mixed within a block. DSP elements can be concatenated.

The resources in each sysDSP block can be configured to support the following four elements:

- MULT (Multiply)
- MAC (Multiply, Accumulate)
- MULTADDSUB (Multiply, Addition/Subtraction)
- MULTADDSUBSUM (Multiply, Addition/Subtraction, Accumulate)

The number of elements available in each block depends on the width selected from the three available options: x9, x18, and x36. A number of these elements are concatenated for highly parallel implementations of DSP functions. Table 2-6 shows the capabilities of the block.

Table 2-6. Maximum Number of Elements in a Block	
--	--

Width of Multiply	x9	x18	x36
MULT	8	4	1
MAC	2	2	—
MULTADDSUB	4	2	—
MULTADDSUBSUM	2	1	—

Some options are available in four elements. The input register in all the elements can be directly loaded or can be loaded as shift register from previous operand registers. By selecting 'dynamic operation' the following operations are possible:



- In the 'Signed/Unsigned' options the operands can be switched between signed and unsigned on every cycle.
- In the 'Add/Sub' option the Accumulator can be switched between addition and subtraction on every cycle.
- The loading of operands can switch between parallel and serial operations.

MULT sysDSP Element

This multiplier element implements a multiply with no addition or accumulator nodes. The two operands, A and B, are multiplied and the result is available at the output. The user can enable the input/output and pipeline registers. Figure 2-20 shows the MULT sysDSP element.

Figure 2-20. MULT sysDSP Element

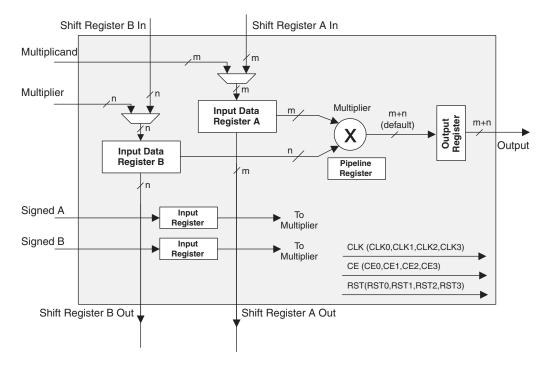




Table 2-11. PIO Signal List

Name	Туре	Description
CE	Control from the core	Clock enables for input and output block flip-flops
CLK	Control from the core	System clocks for input and output blocks
ECLK1, ECLK2	Control from the core	Fast edge clocks
LSR	Control from the core	Local Set/Reset
GSRN	Control from routing	Global Set/Reset (active low)
INCK ²	Input to the core	Input to Primary Clock Network or PLL reference inputs
DQS	Input to PIO	DQS signal from logic (routing) to PIO
INDD	Input to the core	Unregistered data input to core
INFF	Input to the core	Registered input on positive edge of the clock (CLK0)
IPOS0, IPOS1	Input to the core	Double data rate registered inputs to the core
QPOS0 ¹ , QPOS1 ¹	Input to the core	Gearbox pipelined inputs to the core
QNEG0 ¹ , QNEG1 ¹	Input to the core	Gearbox pipelined inputs to the core
OPOS0, ONEG0, OPOS2, ONEG2	Output data from the core	Output signals from the core for SDR and DDR operation
OPOS1 ONEG1	Tristate control from the core	Signals to Tristate Register block for DDR operation
DEL[3:0]	Control from the core	Dynamic input delay control bits
TD	Tristate control from the core	Tristate signal from the core used in SDR operation
DDRCLKPOL	Control from clock polarity bus	Controls the polarity of the clock (CLK0) that feed the DDR input block
DQSXFER	Control from core	Controls signal to the Output block

1. Signals available on left/right/bottom only.

2. Selected I/O.

PIO

The PIO contains four blocks: an input register block, output register block, tristate register block and a control logic block. These blocks contain registers for operating in a variety of modes along with necessary clock and selection logic.

Input Register Block

The input register blocks for PIOs contain delay elements and registers that can be used to condition high-speed interface signals, such as DDR memory interfaces and source synchronous interfaces, before they are passed to the device core. Figure 2-26 shows the diagram of the input register block.

Input signals are fed from the sysIO buffer to the input register block (as signal DI). If desired, the input signal can bypass the register and delay elements and be used directly as a combinatorial signal (INDD), a clock (INCK) and, in selected blocks, the input to the DQS delay block. If an input delay is desired, designers can select either a fixed delay or a dynamic delay DEL[3:0]. The delay, if selected, reduces input register hold time requirements when using a global clock.

The input block allows three modes of operation. In the Single Data Rate (SDR) mode, the data is registered, by one of the registers in the SDR Sync register block, with the system clock. In DDR mode two registers are used to sample the data on the positive and negative edges of the DQS signal which creates two data streams, D0 and D2. D0 and D2 are synchronized with the system clock before entering the core. Further information on this topic can be found in the DDR Memory Support section of this data sheet.

By combining input blocks of the complementary PIOs and sharing registers from output blocks, a gearbox function can be implemented, that takes a double data rate signal applied to PIOA and converts it as four data streams, IPOS0A, IPOS1A, IPOS0B and IPOS1B. Figure 2-26 shows the diagram using this gearbox function. For more information on this topic, please see TN1138, LatticeXP2 High Speed I/O Interface.



Table 2-12. Supported Input Standards

Input Standard	V _{REF} (Nom.)	V _{CCIO} ¹ (Nom.)
Single Ended Interfaces		1
LVTTL	—	—
LVCMOS33	—	—
LVCMOS25		—
LVCMOS18		1.8
LVCMOS15	—	1.5
LVCMOS12	—	—
PCI33		—
HSTL18 Class I, II	0.9	—
HSTL15 Class I	0.75	—
SSTL33 Class I, II	1.5	—
SSTL25 Class I, II	1.25	—
SSTL18 Class I, II	0.9	—
Differential Interfaces		
Differential SSTL18 Class I, II	—	—
Differential SSTL25 Class I, II		—
Differential SSTL33 Class I, II	—	-
Differential HSTL15 Class I	—	-
Differential HSTL18 Class I, II	—	—
LVDS, MLVDS, LVPECL, BLVDS, RSDS	—	—

1. When not specified, V_{CCIO} can be set anywhere in the valid operating range (page 3-1).



LatticeXP2 Family Data Sheet DC and Switching Characteristics

September 2014

Data Sheet DS1009

Absolute Maximum Ratings^{1, 2, 3}

Supply Voltage V _{CC} 0.5 to 1.32V
Supply Voltage V_{CCAUX} \ldots -0.5 to 3.75V
Supply Voltage $V_{CCJ} \dots \dots \dots \dots 0.5$ to $3.75V$
Supply Voltage $V_{\mbox{\scriptsize CCPLL}}{}^4.\ldots\ldots$ -0.5 to 3.75V
Output Supply Voltage V_{CCIO} \ldots 0.5 to 3.75V
Input or I/O Tristate Voltage Applied $^5,\ldots\ldots$ -0.5 to 3.75V
Storage Temperature (Ambient) $\ldots \ldots$ -65 to 150°C
Junction Temperature Under Bias (Tj) +125°C

1. Stress above those listed under the "Absolute Maximum Ratings" may cause permanent damage to the device. Functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

2. Compliance with the Lattice <u>Thermal Management</u> document is required.

3. All voltages referenced to GND.

4. V_{CCPLL} only available on csBGA, PQFP and TQFP packages.

5. Overshoot and undershoot of -2V to (V_{IHMAX} + 2) volts is permitted for a duration of <20 ns.

Recommended Operating Conditions

Symbol	Parameter	Min.	Max.	Units
V _{CC}	Core Supply Voltage	1.14	1.26	V
V _{CCAUX} ^{4, 5}	Auxiliary Supply Voltage	3.135	3.465	V
V _{CCPLL} ¹	PLL Supply Voltage	3.135	3.465	V
V _{CCIO} ^{2, 3, 4}	I/O Driver Supply Voltage	1.14	3.465	V
V _{CCJ} ²	Supply Voltage for IEEE 1149.1 Test Access Port	1.14	3.465	V
t _{JCOM}	Junction Temperature, Commercial Operation	0	85	°C
t _{JIND}	Junction Temperature, Industrial Operation	-40	100	°C

1. V_{CCPLL} only available on csBGA, PQFP and TQFP packages.

If V_{CCIO} or V_{CCJ} is set to 1.2 V, they must be connected to the same power supply as V_{CC}. If V_{CCIO} or V_{CCJ} is set to 3.3V, they must be connected to the same power supply as V_{CCAUX}.

3. See recommended voltages by I/O standard in subsequent table.

4. To ensure proper I/O behavior, V_{CCIO} must be turned off at the same time or earlier than V_{CCAUX} .

5. In fpBGA and ftBGA packages, the PLLs are connected to, and powered from, the auxiliary power supply.

On-Chip Flash Memory Specifications

Symbol			Units
Nanaaaya	Flash Programming Cycles per t _{RETENTION} ¹	10,000 Cycles	
NPROGCYC	Flash Functional Programming Cycles	100,000	Oycles

1. The minimum data retention, t_{RETENTION}, is 20 years.

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Programming and Erase Flash Supply Current^{1, 2, 3, 4, 5}

Over Recommended Operating Conditions

Symbol	Parameter	Device	Typical (25°C, Max. Supply) ⁶	Units
		XP2-5	17	mA
		XP2-8	21	mA
I _{CC}	Core Power Supply Current	XP2-17	28	mA
		XP2-30	36	mA
		XP2-5 17 XP2-8 21 XP2-17 28 XP2-30 36 XP2-40 50 XP2-5 64 XP2-8 66 XP2-17 83 XP2-30 87 XP2-40 88 ent (per PLL) 0.1 rrent (per Bank) 5	50	mA
		XP2-5	64	mA
		XP2-8	66	mA
ICCAUX	Auxiliary Power Supply Current ⁷	XP2-17	83	mA
		XP2-30	87	mA
		XP2-40	88	mA
ICCPLL	PLL Power Supply Current (per PLL)		0.1	mA
I _{CCIO}	Bank Power Supply Current (per Bank)		5	mA
ICCJ	V _{CCJ} Power Supply Current ⁸		14	mA

1. For further information on supply current, please see TN1139, Power Estimation and Management for LatticeXP2 Devices.

2. Assumes all outputs are tristated, all inputs are configured as LVCMOS and held at the V_{CCIO} or GND.

3. Frequency 0 MHz (excludes dynamic power from FPGA operation).

4. A specific configuration pattern is used that scales with the size of the device; consists of 75% PFU utilization, 50% EBR, and 25% I/O configuration.

5. Bypass or decoupling capacitor across the supply.

6. $T_J = 25^{\circ}C$, power supplies at nominal voltage.

In fpBGA and ftBGA packages the PLLs are connected to and powered from the auxiliary power supply. For these packages, the actual
auxiliary supply current is the sum of I_{CCAUX} and I_{CCPLL}. For csBGA, PQFP and TQFP packages the PLLs are powered independent of the
auxiliary power supply.

8. When programming via JTAG.



Table 3-1. LVDS25E DC Conditions

Parameter	Description	Typical	Units
V _{CCIO}	Output Driver Supply (+/-5%)	2.50	V
Z _{OUT}	Driver Impedance	20	Ω
R _S	Driver Series Resistor (+/-1%)	158	Ω
R _P	Driver Parallel Resistor (+/-1%)	140	Ω
R _T	Receiver Termination (+/-1%)	100	Ω
V _{OH}	Output High Voltage (after R _P)	1.43	V
V _{OL}	Output Low Voltage (after R _P)	1.07	V
V _{OD}	Output Differential Voltage (After R _P)	0.35	V
V _{CM}	Output Common Mode Voltage	1.25	V
Z _{BACK}	Back Impedance	100.5	Ω
I _{DC}	DC Output Current	6.03	mA

LVCMOS33D

All I/O banks support emulated differential I/O using the LVCMOS33D I/O type. This option, along with the external resistor network, provides the system designer the flexibility to place differential outputs on an I/O bank with 3.3V VCCIO. The default drive current for LVCMOS33D output is 12mA with the option to change the device strength to 4mA, 8mA, 16mA or 20mA. Follow the LVCMOS33 specifications for the DC characteristics of the LVCMOS33D.



LatticeXP2 External Switching Characteristics

			-7		-6		-5		
Parameter	Description	Device	Min.	Max.	Min.	Max.	Min.	Max.	Units
General I/O Pi	n Parameters (using Primary Clo	ck without I	PLL) ¹	1	1			1	
		XP2-5	—	3.80		4.20	—	4.60	ns
		XP2-8	—	3.80	—	4.20	—	4.60	ns
t _{CO}	Clock to Output - PIO Output Register	XP2-17	—	3.80	—	4.20	—	4.60	ns
		XP2-30	—	4.00	—	4.40	—	4.90	ns
		XP2-40	—	4.00	—	4.40	—	4.90	ns
		XP2-5	0.00		0.00	—	0.00		ns
		XP2-8	0.00	_	0.00	—	0.00	_	ns
t _{SU}	Clock to Data Setup - PIO Input Register	XP2-17	0.00	_	0.00	—	0.00	_	ns
		XP2-30	0.00	_	0.00	—	0.00	_	ns
		XP2-40	0.00		0.00	—	0.00		ns
		XP2-5	1.40		1.70	—	1.90		ns
		XP2-8	1.40	_	1.70	—	1.90	_	ns
t _H	Clock to Data Hold - PIO Input Register	XP2-17	1.40		1.70	—	1.90	—	ns
		XP2-30	1.40		1.70	—	1.90		ns
		XP2-40	1.40		1.70	—	1.90		ns
		XP2-5	1.40		1.70	—	1.90		ns
		XP2-8	1.40		1.70	—	1.90		ns
t _{SU_DEL}	Clock to Data Setup - PIO Input Register with Data Input Delay	XP2-17	1.40	_	1.70	—	1.90	_	ns
	lingibion with Data input Dolay	XP2-30	1.40		1.70	—	1.90	—	ns
		XP2-40	1.40		1.70	—	1.90		ns
		XP2-5	0.00		0.00	—	0.00		ns
		XP2-8	0.00		0.00	—	0.00	—	ns
t _{H_DEL}	Clock to Data Hold - PIO Input Register with Input Data Delay	XP2-17	0.00		0.00	—	0.00	—	ns
		XP2-30	0.00		0.00	—	0.00		ns
		XP2-40	0.00		0.00	—	0.00	—	ns
f _{MAX_IO}	Clock Frequency of I/O and PFU Register	XP2	_	420	—	357	—	311	MHz
General I/O Pi	n Parameters (using Edge Clock	without PLI	_) ¹						
		XP2-5	—	3.20	_	3.60	—	3.90	ns
		XP2-8	_	3.20		3.60	—	3.90	ns
t _{COE}	Clock to Output - PIO Output Register	XP2-17	—	3.20	_	3.60	—	3.90	ns
		XP2-30	_	3.20		3.60		3.90	ns
		XP2-40	_	3.20		3.60	—	3.90	ns
		XP2-5	0.00		0.00	—	0.00		ns
		XP2-8	0.00		0.00	—	0.00	—	ns
t _{SUE}	Clock to Data Setup - PIO Input Register	XP2-17	0.00	—	0.00	—	0.00	—	ns
		XP2-30	0.00	—	0.00	—	0.00	—	ns
		XP2-40	0.00	—	0.00	—	0.00	—	ns

Over Recommended Operating Conditions



LatticeXP2 External Switching Characteristics (Continued)

			-7		-6		-5		
Parameter	Description	Device	Min.	Max.	Min.	Max.	Min.	Max.	Units
		XP2-5	1.00	—	1.30	—	1.60	—	ns
		XP2-8	1.00	—	1.30	—	1.60	—	ns
t _{HE}	Clock to Data Hold - PIO Input Register	XP2-17	1.00	—	1.30	—	1.60	—	ns
		XP2-30	1.20	—	1.60	—	1.90	—	ns
		XP2-40	1.20	—	1.60	—	1.90	—	ns
		XP2-5	1.00	—	1.30	—	1.60	—	ns
		XP2-8	1.00	—	1.30	—	1.60	—	ns
t _{SU_DELE}	Clock to Data Setup - PIO Input Register with Data Input Delay	XP2-17	1.00	—	1.30	—	1.60	—	ns
	Tiegister with Data input Delay	XP2-30	1.20	—	1.60	—	1.90	—	ns
		XP2-40	1.20	—	1.60	—	1.90	—	ns
		XP2-5	0.00	—	0.00	—	0.00	—	ns
		XP2-8	0.00	—	0.00	—	0.00	—	ns
t _{H_DELE}	Clock to Data Hold - PIO Input Register with Input Data Delay	XP2-17	0.00	—	0.00	—	0.00	—	ns
	negister with input Data Delay	XP2-30	0.00	—	0.00	—	0.00	—	ns
		XP2-40	0.00	_	0.00	—	0.00	—	ns
f _{MAX_IOE}	Clock Frequency of I/O and PFU Register	XP2	_	420	_	357	—	311	MHz
General I/O Pi	in Parameters (using Primary Clo	ck with PLL	.)1		1				
	Clock to Output - PIO Output Register	XP2-5	—	3.00	_	3.30	—	3.70	ns
		XP2-8	—	3.00	—	3.30	—	3.70	ns
t _{COPLL}		XP2-17	—	3.00	—	3.30	—	3.70	ns
		XP2-30	—	3.00	—	3.30	—	3.70	ns
		XP2-40	—	3.00	—	3.30	—	3.70	ns
		XP2-5	1.00	—	1.20	—	1.40	—	ns
		XP2-8	1.00	—	1.20	—	1.40	—	ns
t _{SUPLL}	Clock to Data Setup - PIO Input Register	XP2-17	1.00	—	1.20	—	1.40	—	ns
		XP2-30	1.00	—	1.20	—	1.40	—	ns
		XP2-40	1.00	—	1.20	—	1.40	—	ns
		XP2-5	0.90	—	1.10	—	1.30	—	ns
		XP2-8	0.90	—	1.10	—	1.30	—	ns
t _{HPLL}	Clock to Data Hold - PIO Input Register	XP2-17	0.90	—	1.10	—	1.30	—	ns
		XP2-30	1.00	—	1.20	—	1.40	—	ns
		XP2-40	1.00	—	1.20	—	1.40	—	ns
		XP2-5	1.90	—	2.10	—	2.30	—	ns
		XP2-8	1.90		2.10	—	2.30	_	ns
t _{SU_DELPLL}	Clock to Data Setup - PIO Input Register with Data Input Delay	XP2-17	1.90	_	2.10	—	2.30	—	ns
-		XP2-30	2.00	—	2.20	—	2.40	—	ns
		XP2-40	2.00	_	2.20	—	2.40	_	ns

Over Recommended Operating Conditions



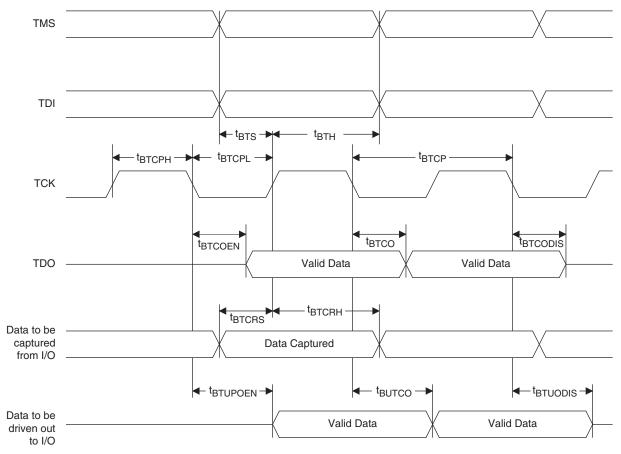
LatticeXP2 Internal Switching Characteristics¹

		-	7	-	6	-	5]	
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Units	
	ic Mode Timing							••	
t _{LUT4_PFU}	LUT4 delay (A to D inputs to F output)	_	0.216	_	0.238	_	0.260	ns	
t _{LUT6_PFU}	LUT6 delay (A to D inputs to OFX output)	_	0.304	_	0.399	_	0.494	ns	
t _{LSR_PFU}	Set/Reset to output of PFU (Asyn- chronous)	_	0.720	_	0.769	—	0.818	ns	
t _{SUM_PFU}	Clock to Mux (M0,M1) Input Setup Time	0.154	_	0.151	_	0.148	_	ns	
t _{HM_PFU}	Clock to Mux (M0,M1) Input Hold Time	-0.061	_	-0.057	_	-0.053	_	ns	
t _{SUD_PFU}	Clock to D input setup time	0.061	—	0.077	—	0.093	—	ns	
t _{HD_PFU}	Clock to D input hold time	0.002		0.003		0.003		ns	
t _{CK2Q_PFU}	Clock to Q delay, (D-type Register Configuration)	_	0.342	—	0.363	—	0.383	ns	
t _{RSTREC_PFU}	Asynchronous reset recovery time for PFU Logic	—	0.520	—	0.634	_	0.748	ns	
t _{RST_PFU}	Asynchronous reset time for PFU Logic	_	0.720	—	0.769	_	0.818	ns	
PFU Dual Por	t Memory Mode Timing								
t _{CORAM_PFU}	Clock to Output (F Port)	—	1.082	—	1.267	—	1.452	ns	
t _{SUDATA_PFU}	Data Setup Time	-0.206	—	-0.240	_	-0.274	—	ns	
t _{HDATA_PFU}	Data Hold Time	0.239	_	0.275	—	0.312	—	ns	
t _{SUADDR_PFU}	Address Setup Time	-0.294	_	-0.333	_	-0.371		ns	
t _{HADDR_PFU}	Address Hold Time	0.295	—	0.333	_	0.371	—	ns	
t _{SUWREN_PFU}	Write/Read Enable Setup Time	-0.146	—	-0.169	_	-0.193	—	ns	
t _{HWREN_PFU}	Write/Read Enable Hold Time	0.158	_	0.182	_	0.207	—	ns	
PIO Input/Out	put Buffer Timing								
t _{IN_PIO}	Input Buffer Delay (LVCMOS25)	_	0.858	—	0.766	—	0.674	ns	
t _{OUT_PIO}	Output Buffer Delay (LVCMOS25)		1.561	_	1.403	—	1.246	ns	
IOLOGIC Inpu	it/Output Timing								
t _{SUI_PIO}	Input Register Setup Time (Data Before Clock)	0.583	—	0.893	_	1.201	—	ns	
t _{HI_PIO}	Input Register Hold Time (Data after Clock)	0.062	—	0.322	_	0.482	—	ns	
t _{COO_PIO}	Output Register Clock to Output Delay	_	0.608	_	0.661	_	0.715	ns	
t _{SUCE_PIO}	Input Register Clock Enable Setup Time	0.032	_	0.037		0.041	—	ns	
t _{HCE_PIO}	Input Register Clock Enable Hold Time	-0.022	_	-0.025	_	-0.028	_	ns	
t _{SULSR_PIO}	Set/Reset Setup Time	0.184	—	0.201		0.217	—	ns	
t _{HLSR_PIO}	Set/Reset Hold Time	-0.080		-0.086		-0.093	_	ns	
t _{RSTREC_PIO}	Asynchronous reset recovery time for IO Logic	0.228	_	0.247	_	0.266	_	ns	

Over Recommended Operating Conditions









Part Number	Voltage	Grade	Package	Pins	Temp.	LUTs (k)
LFXP2-40E-5F484C	1.2V	-5	fpBGA	484	COM	40
LFXP2-40E-6F484C	1.2V	-6	fpBGA	484	COM	40
LFXP2-40E-7F484C	1.2V	-7	fpBGA	484	COM	40
LFXP2-40E-5F672C	1.2V	-5	fpBGA	672	COM	40
LFXP2-40E-6F672C	1.2V	-6	fpBGA	672	COM	40
LFXP2-40E-7F672C	1.2V	-7	fpBGA	672	COM	40

Industrial

Part Number	Voltage	Grade	Package	Pins	Temp.	LUTs (k)
LFXP2-5E-5M132I	1.2V	-5	csBGA	132	IND	5
LFXP2-5E-6M132I	1.2V	-6	csBGA	132	IND	5
LFXP2-5E-6FT256I	1.2V	-6	ftBGA	256	IND	5

Part Number	Voltage	Grade	Package	Pins	Temp.	LUTs (k)
LFXP2-8E-5M132I	1.2V	-5	csBGA	132	IND	8
LFXP2-8E-6M132I	1.2V	-6	csBGA	132	IND	8
LFXP2-5E-5FT256I	1.2V	-5	ftBGA	256	IND	5
LFXP2-8E-5FT256I	1.2V	-5	ftBGA	256	IND	8
LFXP2-8E-6FT256I	1.2V	-6	ftBGA	256	IND	8

Part Number	Voltage	Grade	Package	Pins	Temp.	LUTs (k)
LFXP2-17E-5FT256I	1.2V	-5	ftBGA	256	IND	17
LFXP2-17E-6FT256I	1.2V	-6	ftBGA	256	IND	17
LFXP2-17E-5F484I	1.2V	-5	fpBGA	484	IND	17
LFXP2-17E-6F484I	1.2V	-6	fpBGA	484	IND	17

Part Number	Voltage	Grade	Package	Pins	Temp.	LUTs (k)
LFXP2-30E-5FT256I	1.2V	-5	ftBGA	256	IND	30
LFXP2-30E-6FT256I	1.2V	-6	ftBGA	256	IND	30
LFXP2-30E-5F484I	1.2V	-5	fpBGA	484	IND	30
LFXP2-30E-6F484I	1.2V	-6	fpBGA	484	IND	30
LFXP2-30E-5F672I	1.2V	-5	fpBGA	672	IND	30
LFXP2-30E-6F672I	1.2V	-6	fpBGA	672	IND	30



Part Number	Voltage	Grade	Package	Pins	Temp.	LUTs (k)
LFXP2-40E-5F484I	1.2V	-5	fpBGA	484	IND	40
LFXP2-40E-6F484I	1.2V	-6	fpBGA	484	IND	40
LFXP2-40E-5F672I	1.2V	-5	fpBGA	672	IND	40
LFXP2-40E-6F672I	1.2V	-6	fpBGA	672	IND	40



LatticeXP2 Family Data Sheet Revision History

September 2014

Data Sheet DS1009

Revision History

	Version	Section	Change Summary
May 2007	01.1		Initial release.
September 2007	01.2	DC and Switching Characteristics	Added JTAG Port Timing Waveforms diagram.
			Updated sysCLOCK PLL Timing table.
		Pinout Information	Added Thermal Management text section.
February 2008	01.3	Architecture	Added LVCMOS33D to Supported Output Standards table.
			Clarified: "This Flash can be programmed through either the JTAG or Slave SPI ports of the device. The SRAM configuration space can also be infinitely reconfigured through the JTAG and Master SPI ports."
			Added External Slave SPI Port to Serial TAG Memory section. Updated Serial TAG Memory diagram.
		DC and Switching Characteristics	Updated Flash Programming Specifications table.
			Added "8W" specification to Hot Socketing Specifications table.
			Updated Timing Tables
			Clarifications for IIH in DC Electrical Characteristics table.
			Added LVCMOS33D section
			Updated DOA and DOA (Regs) to EBR Timing diagrams.
			Removed Master Clock Frequency and Duty Cycle sections from the LatticeXP2 sysCONFIG Port Timing Specifications table. These are listed on the On-chip Oscillator and Configuration Master Clock Characteristics table.
			Changed CSSPIN to CSSPISN in description of $t_{SCS},t_{SCSS},$ and t_{SCSH} parameters. Removed t_{SOE} parameter.
			Clarified On-chip Oscillator documentation
			Added Switching Test Conditions
		Pinout Information	Added "True LVDS Pairs Bonding Out per Bank," "DDR Banks Bonding Out per I/O Bank," and "PCI capable I/Os Bonding Out per Bank" to Pin Information Summary in place of previous blank table "PCI and DDR Capabilities of the Device-Package Combinations"
			Removed pinout listing. This information is available on the LatticeXP2 product web pages
		Ordering Information	Added XP2-17 "8W" and all other family OPNs.
April 2008	01.4	DC and Switching	Updated Absolute Maximum Ratings footnotes.
		Characteristics	Updated Recommended Operating Conditions Table footnotes.
			Updated Supply Current (Standby) Table
			Updated Initialization Supply Current Table
			Updated Programming and Erase Flash Supply Current Table
			Updated Register to Register Performance Table
			Updated LatticeXP2 External Switching Characteristics Table
			Updated LatticeXP2 Internal Switching Characteristics Table
			Updated sysCLOCK PLL Timing Table

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Date	Version	Section	Change Summary		
April 2008	01.4	DC and Switching	Updated Flash Download Time (From On-Chip Flash to SRAM) Table		
(cont.)	(cont.)	Characteristics (cont.)	Updated Flash Program Time Table		
			Updated Flash Erase Time Table		
			Updated FlashBAK (from EBR to Flash) Table		
			Updated Hot Socketing Specifications Table footnotes		
		Pinout Information	Updated Signal Descriptions Table		
June 2008	01.5	Architecture	Removed Read-Before-Write sysMEM EBR mode.		
			Clarification of the operation of the secondary clock regions.		
		DC and Switching Characteristics	Removed Read-Before-Write sysMEM EBR mode.		
		Pinout Information	Updated DDR Banks Bonding Out per I/O Bank section of Pin Informa- tion Summary Table.		
August 2008	01.6	—	Data sheet status changed from preliminary to final.		
		Architecture	Clarification of the operation of the secondary clock regions.		
		DC and Switching Characteristics	Removed "8W" specification from Hot Socketing Specifications table.		
			Removed "8W" footnote from DC Electrical Characteristics table.		
			Updated Register-to-Register Performance table.		
		Ordering Information	Removed "8W" option from Part Number Description.		
			Removed XP2-17 "8W" OPNs.		
April 2011	01.7	DC and Switching Characteristics	Recommended Operating Conditions table, added footnote 5.		
			On-Chip Flash Memory Specifications table, added footnote 1.		
			BLVDS DC Conditions, corrected column title to be Z0 = 90 ohms.		
			sysCONFIG Port Timing Specifications table, added footnote 1 for to the total		
January 2012	01.8	Multiple	Added support for Lattice Diamond design software.		
		Architecture	Corrected information regarding SED support.		
		DC and Switching Characteristics	Added reference to ESD Performance Qualification Summary informa- tion.		
May 2013	01.9	All	Updated document with new corporate logo.		
		Architecture	Architecture Overview – Added information on the state of the register on power up and after configuration.		
			Added information regarding SED support.		
		DC and Switching Characteristics	Removed Input Clock Rise/Fall Time 1ns max from the sysCLOCK PLL Timing table.		
		Ordering Information	Updated topside mark in Ordering Information diagram.		
March 2014	02.0	Architecture	Updated Typical sysIO I/O Behavior During Power-up section. Added information on POR signal deactivation.		
August 2014	02.1	Architecture	Updated Typical sysIO I/O Behavior During Power-up section. Described user I/Os during power up and before FPGA core logic is active.		
September 2014	2.2	DC and Switching Characteristics	Updated Switching Test Conditions section. Re-linked missing figure.		